

<b>Notice of References Cited</b>	Application/Control No. 10/034,084 09/849,269	Applicant(s)/Patent Under Reexamination CHEN, YEE YVONNE	
	Examiner Kishor Mayekar	Art Unit 1753	Page 1 of 1

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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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